


<b>Search Notes</b>  	<b>Application/Control No.</b>  10802010	<b>Applicant(s)/Patent Under Reexamination</b>  CHUNG ET AL.
	<b>Examiner</b>  Rutz, Jared I	<b>Art Unit</b>  2187

SEARCHED			
Class	Subclass	Date	Examiner

SEARCH NOTES		
Search Notes	Date	Examiner
inventor search in EAST and PALM	8/18/2006	jir
text and text limited classification search in EAST, see search history	8/18/2006	jir
Updated search in EAST	2/8/2007	jir
Updated search in EAST	6/6/2007	jir
updated search in EAST	11/9/2007	jir
updated search in EAST	3/28/2008	jir
updated search in EAST	6/23/2008	jir
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internet search using google.com and scholar.google.com	12/16/2008	jir
updated search in EAST	6/8/2009	jir

INTERFERENCE SEARCH			
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